

# MAZE062D

## Silicon planar type

For surge absorption circuit

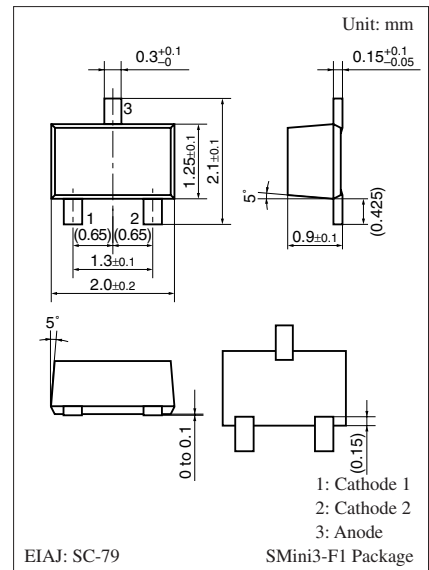
### ■ Features

- Low joint capacity zener diode

### ■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

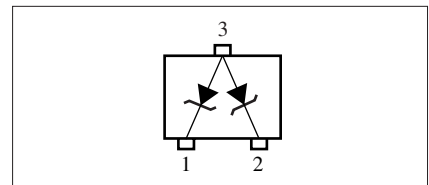
Parameter	Symbol	Rating	Unit
Repetitive peak forward current	$I_{FRM}$	200	mA
Power dissipation *	$P_D$	150	mW
Junction temperature	$T_j$	150	$^\circ\text{C}$
Storage temperature	$T_{stg}$	-55 to +150	$^\circ\text{C}$

Note) \*:  $P_D = 200$  mW achieved with a printed circuit board.



Marking Symbol: 6.2C

Internal connection



### ■ Electrical Characteristics $T_a = 25^\circ\text{C} \pm 3^\circ\text{C}$

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Forward voltage	$V_F$	$I_F = 10$ mA		0.9	1.0	V
Zener voltage *	$V_Z$	$I_Z = 5$ mA	5.9		6.5	V
Zener rise operating resistance	$R_{ZK}$	$I_Z = 0.5$ mA			100	$\Omega$
Zener operating resistance	$R_Z$	$I_Z = 5$ mA			30	$\Omega$
Reverse current	$I_R$	$V_R = 5.5$ V			3	$\mu\text{A}$
Terminal capacitance	$C_t$	$V_R = 0$ V, $f = 1$ MHz		8		pF

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7031 measuring methods for diodes.

2. Absolute frequency of input and output is 5 MHz.

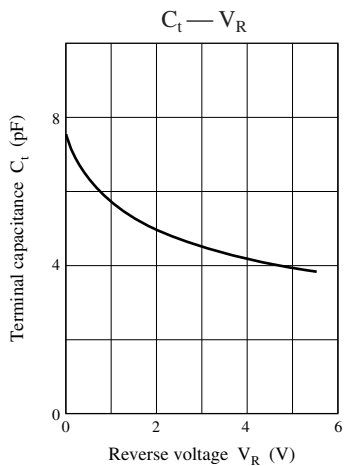
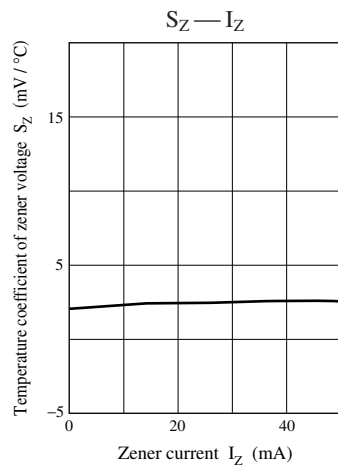
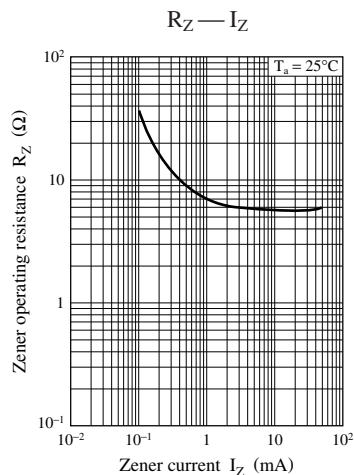
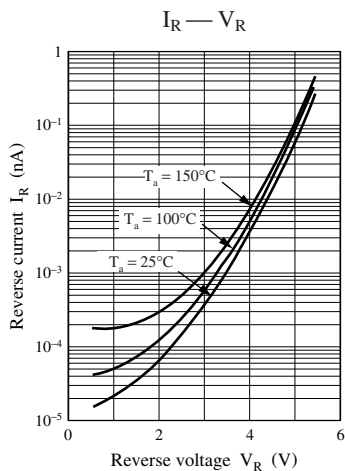
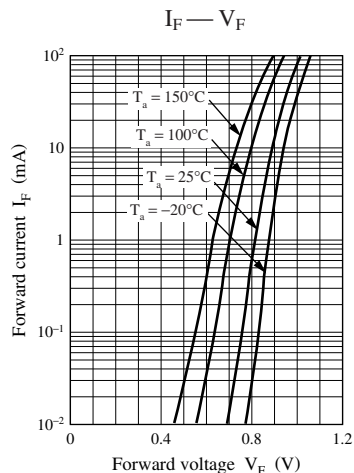
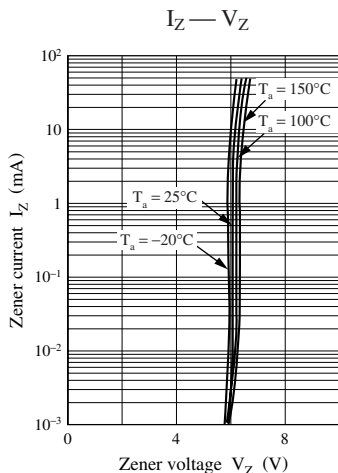
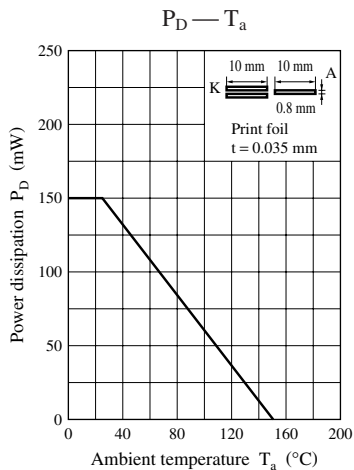
3. Electrostatic breakdown voltage:  $\pm 15$  kV

Test method: IEC-801 (C = 150 pF, R = 330  $\Omega$ , Contact discharge: 10 times)

Test unit: ESS-200AX

4. \*: The  $V_Z$  value is for the temperature of  $25^\circ\text{C}$ . In other cases, carry out the temperature compensation.

Guaranteed at 20 ms after power application.



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